


PCN Number:	20130322000		PCN Date:	03/25/2013	
Title:	Qualification of CAR as an Additional Assembly Site for Select Devices in the SSOP (DB) Package				
Customer Contact:	PCN Manager	Phone:	+1(214)480-6037	Dept:	Quality Services
Proposed 1st Ship Date:	06/25/2013		Estimated Sample Availability:	Date provided at sample request	
Change Type:					
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification
<input type="checkbox"/>	Test Site	<input checked="" type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process
PCN Details					
Description of Change:					
Qualification of CAR as an Additional Assembly Site for Select Devices in the SSOP (DB) Package which are currently assembled at CRS.					
Reason for Change:					
Continuity of supply.					
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):					
None.					
Changes to product identification resulting from this PCN:					
Sample Product Shipping Label (not actual product label)					
Assembly Site					
CRS		Assembly Site Origin (22L)		ASO: CRS	
CAR		Assembly Site Origin (22L)		ASO: CAR	
					

Product Affected:

DAC7613E	DAC7615E	DAC7617E	DAC7631E
DAC7613EB	DAC7615EB	DAC7617EB	DAC7631EB
DAC7613EBG4	DAC7615EBG4	DAC7617EBG4	DAC7631EBG4
DAC7613EG4	DAC7615EG4	DAC7617EG4	DAC7631EG4
DAC7614E	DAC7616E	DAC7621E	DAC7731E
DAC7614EB	DAC7616EB	DAC7621EB	DAC7731EB
DAC7614EBG4	DAC7616EBG4	DAC7621EBG4	DAC7731EBG4
DAC7614EG4	DAC7616EG4	DAC7621EG4	DAC7731EG4

DB Qualification Data: Approved 3/21/2013

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qual Device 1 : ADS1213E (MSL 2-260C)**Package Construction Details**

Assembly Site:	CAR	Mold Compound:	438360
# Pins-Designator, Family:	28-DB, SSOP	Mount Compound:	434165
Leadframe (Finish, Base):	NiPdAu, Cu	Bond Wire:	1.3 Mil Dia., AU

Qualification: Plan Test Results

Reliability Test	Conditions	Sample Size Pass/Fail
**Unbiased HAST	130C/85%RH/33.3 psia (96 Hrs)	77/0
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0
Manufacturability	(Assembly Site)	Pass
Moisture Sensitivity, L2	85C/60%RH/168 Hrs	12/0

Notes: ** Preconditioning sequence Level 2-260C

Qual Device 2 : ADS7871IDB (MSL 2-260C)**Package Construction Details**

Assembly Site:	CAR	Mold Compound:	438358
# Pins-Designator, Family:	28-DB, SSOP	Mount Compound:	434165
Leadframe (Finish, Base):	NiPdAu, Cu	Bond Wire:	1.3 Mil Dia., AU

Qualification: Plan Test Results

Reliability Test	Conditions	Sample Size/Fail
**Unbiased HAST	130C/85%RH/33.3 psia (96 Hrs)	77/0
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0
Manufacturability	(Assembly Site)	Pass
Moisture Sensitivity, L2	85C/60%RH/168 Hrs	12/0

Notes: ** Preconditioning sequence Level 2-260C

Qual Device 3 : ADS825E (MSL 2-260C)**Package Construction Details**

Assembly Site:	CAR	Mold Compound:	438360
# Pins-Designator, Family:	28-DB, SSOP	Mount Compound:	434165
Leadframe (Finish, Base):	NiPdAu, Cu	Bond Wire:	1.3 Mil Dia., AU

Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size/Fail
Solderability	Pb-Free/Solder	22/0
**Unbiased HAST	130C/85%RH/33.3 psia (96 Hrs)	77/0
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0
Manufacturability	(Assembly Site)	Pass
Physical Dimensions	Mechanical drawing	5/0
Moisture Sensitivity, L2	85C/60%RH/168 Hrs	12/0
Notes: ** Preconditioning sequence Level 2-260C		
Qual Device 4 : DAC8820IBDB (MSL 2-260C)		
Package Construction Details		
Assembly Site:	CAR	Mold Compound: 438518
# Pins-Designator, Family:	28-DB, SSOP	Mount Compound: 434165
Leadframe (Finish, Base):	NiPdAu, Cu	Bond Wire: 1.3 Mil Dia., AU
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size/Fail
		Lot 1 Lot 2 Lot 3
Manufacturability	(Assembly Site)	Pass Pass Pass
Solderability	8 Hrs/Stm Age, Pb-Free/Solder	22/0 22/0 -
**Unbiased HAST	130C/85%RH/33.3 psia (96 Hrs)	77/0 77/0 77/0
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0 77/0 77/0
Physical Dimensions	Mechanical drawing	5/0 - -
Moisture Sensitivity, L2	85C/60%RH/168 Hrs	12/0 12/0 -
Notes: ** Preconditioning sequence Level 2-260C		
Qual Device 5 : PGA2505IDB (MSL 2-260C)		
Package Construction Details		
Assembly Site:	CAR	Mold Compound: 438360
# Pins-Designator, Family:	24-DB, SSOP	Mount Compound: 434165
Leadframe (Finish, Base):	NiPdAu, Cu	Bond Wire: 1.3 Mil Dia., AU
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size/Fail
**Unbiased HAST	130C/85%RH/33.3 psia (96 Hrs)	77/0
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0
Manufacturability	(Assembly Site)	Pass
Physical Dimensions	Mechanical drawing	5/0
Moisture Sensitivity, L2	85C/60%RH/168 Hrs	12/0
Notes: ** Preconditioning sequence Level 2-260C		

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com